Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/677,299	HEO ET AL.
Examiner	Art Unit
Erin M. File	2611

SEARCHED					
Class	Subclass	Date	Examiner		
375	346	3/22/2007	EMF		
375	347	3/22/2007	EMF		
455	132	3/22/2007	EMF		
455	296	3/22/2007	EMF		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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See Sear	ext Search ch History ntout	3/22/2007	EMF	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
·	DATE	EXMR		
EAST US PAT, USPGPUB, EPO, JPO DERWENT, IBM (text search only—see search history printout)	3/22/2007	EMF		
Google Patent Search	3/22/2007	EMF ·		
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